

OptiMOS™-5 Power-Transistor





Features

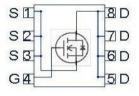
- N-channel Enhancement mode
- AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Green product (RoHS compliant)
- 100% Avalanche tested

Product Summary

V_{DS}	80	V
R _{DS(on)}	3.1	mΩ
I _D	100	Α



Туре	Package	Marking
IAUC100N08S5N031	PG-TDSON-8	5N08031



Maximum ratings, at T_j =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current ¹⁾	ID	T _C =25°C, V _{GS} =10V	100	А
		TC=100 °C, VGS=10 V ²⁾	100	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	400	
Avalanche energy, single pulse ²⁾	E _{AS}	/ _D =50 A	250	mJ
Avalanche current, single pulse	IAS	-	100	А
Gate source voltage	V_{GS}	-	±20	V
Power dissipation	P_{tot}	T _C =25 °C	167	W
Operating and storage temperature	$T_{\rm j},~T_{\rm stg}$	-	-55 +175	°C
IEC climatic category; DIN IEC 68-1	-	-	55/175/56	



Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Thermal characteristics ²⁾						
Thermal resistance, junction - case	R_{thJC}	-	-	-	0.9	K/W

Electrical characteristics, at T_j =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	V _{(BR)DSS}	V _{GS} =0 V, I _D =1 mA	80	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 95 \mu {\rm A}$	2.2	3.0	3.8	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS} = 80 \text{ V}, V_{\rm GS} = 0 \text{ V}, $ $T_{\rm j} = 25 \text{ °C}$	1	0.1	1	μΑ
		V_{DS} =80 V, V_{GS} =0 V, T_{j} =85 °C ²⁾	-	1	20	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	-	100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =6 V, I _D =25 A	-	3.5	4.6	mΩ
		V _{GS} =10 V, I _D =50 A	-	2.7	3.1	
Gate resistance ²⁾	R _G			1.6	-	Ω



Parameter	Symbol Conditions		Values			Unit
			min.	typ.	max.	
Dynamic characteristics ²⁾						
Input capacitance	Ciss		-	4250	5525	pF
Output capacitance	Coss	V _{GS} =0 V, V _{DS} =40 V, f=1 MHz	-	700	910	1
Reverse transfer capacitance	C _{rss}		-	32	48	
Turn-on delay time	t _{d(on)}		-	11	-	ns
Rise time	t _r	V _{DD} =40 V, V _{GS} =10 V,	-	6	-	
Turn-off delay time	$t_{d(off)}$	$I_{\rm D}$ =100 A, $R_{\rm G}$ =3.5 Ω	-	21	-	
Fall time	t_{f}		-	15	-	
Gate Charge Characteristics ²⁾ Gate to source charge	Q_{gs}	<u> </u>		20	26	nC
Gate to drain charge	Q _{gd}	$V_{\rm DD}$ =40 V, $I_{\rm D}$ =50 A, $V_{\rm GS}$ =0 to 10 V	_	14	21	
Gate charge total	Q _g		-	59	76	
Gate plateau voltage	V _{plateau}		-	4.4	-	V
Reverse Diode	•			l		•
Diode continous forward current ¹⁾	Is	T _25 °C	-	-	100	А
Diode pulse current ²⁾	I _{S,pulse}	− T _C =25 °C	-	-	400	
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =50 A, T _j =25 °C	-	0.9	1.2	V
Reverse recovery time ²⁾	t _{rr}	V _R =40 V, I _F =50A,	-	54	-	ns
Reverse recovery charge ²⁾	Q _{rr}	$di_F/dt=100 \text{ A/}\mu\text{s}$	_	94	_	nC

 $^{^{1)}}$ Current is limited by package; with an $R_{\rm thJC}$ = 0.9K/W the chip is able to carry 165A at 25°C

²⁾ Defined by design. Not subject to production test.



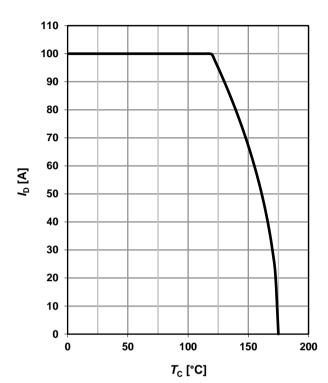
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \ge 6 \text{ V}$$

160 120 80 40 0 0 0 50 100 150 200 T_C [°C]

2 Drain current

$$I_D = f(T_C); V_{GS} \ge 6 \text{ V}$$



3 Safe operating area

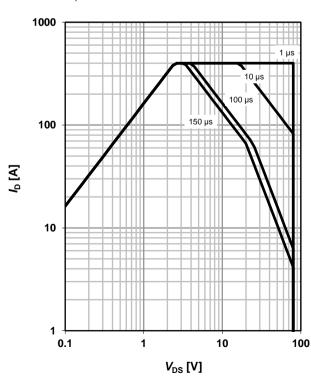
$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

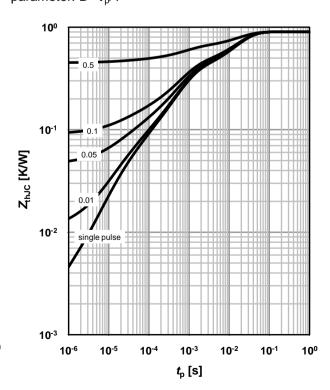
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\text{thJC}} = f(t_{p})$$

parameter: $D=t_p/T$



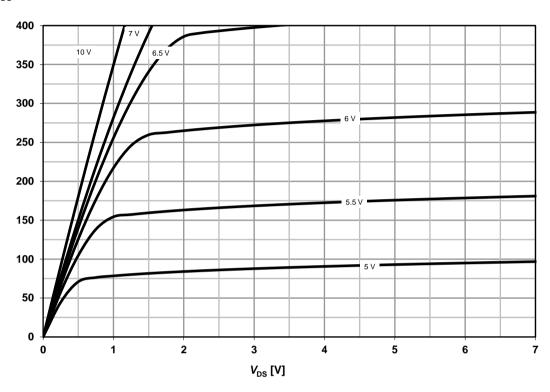




5 Typ. output characteristics

 $I_{D} = f(V_{DS}); T_{j} = 25 \text{ °C}$

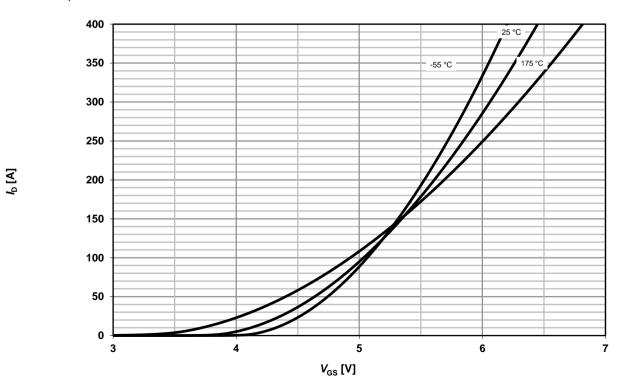
parameter: V_{GS}



7 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 6V$

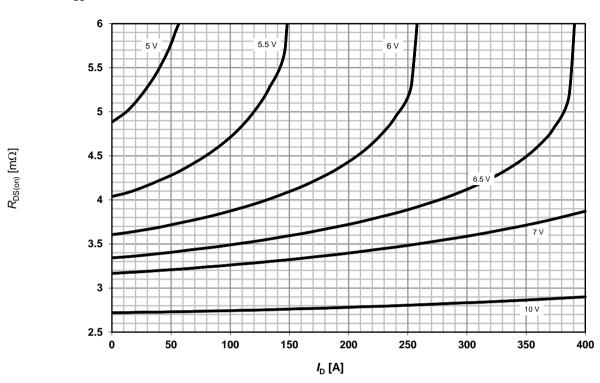
parameter: $T_{\rm j}$



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25 \text{ °C}$

parameter: V_{GS}



8 Typ. drain-source on-state resistance

6.5

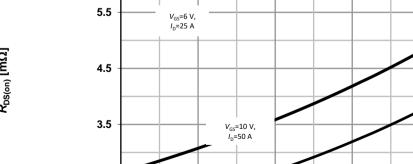
2.5

1.5

-60

 $R_{DS(on)} = f(T_j)$

parameter: V_{GS} ; I_{D}



-20

 $R_{\rm DS(on)}$ [m Ω]

60

*T*_j [°C]

100

140

180

20



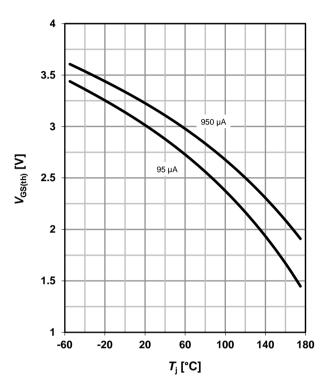
9 Typ. gate threshold voltage

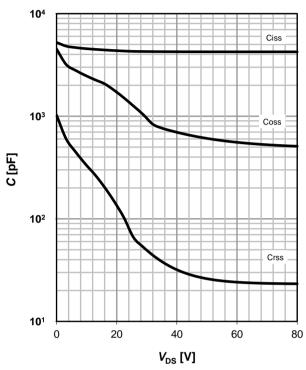
 $V_{GS(th)} = f(T_i); V_{GS} = V_{DS}$

parameter: I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$





11 Typical forward diode characteristicis

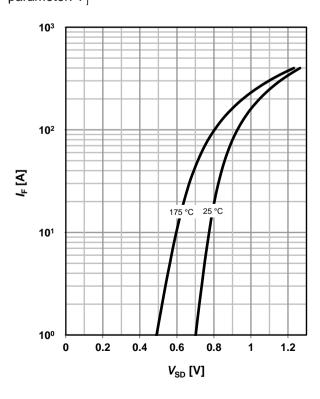
 $IF = f(V_{SD})$

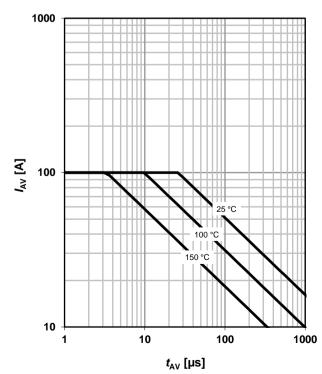
parameter: $T_{\rm j}$

12 Typ. avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}







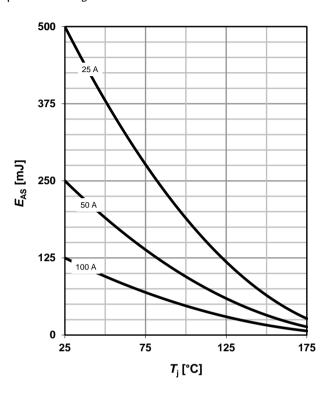
13 Typical avalanche energy

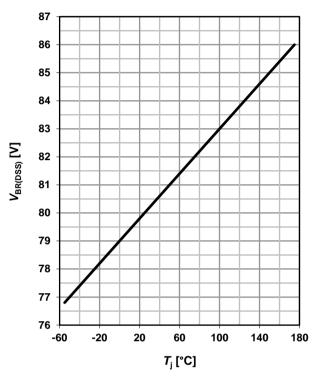
 $E_{AS} = f(T_i)$

parameter: I_D

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_{D,typ} = 1 \text{ mA}$$

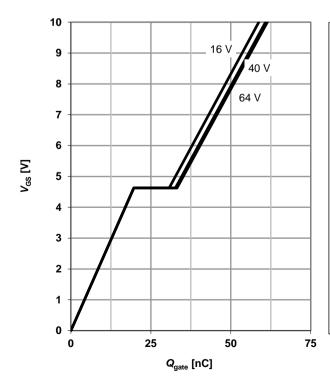




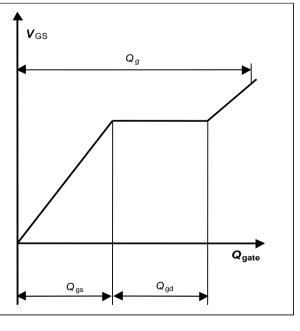
15 Typ. gate charge

 $V_{GS} = f(Q_{gate}); I_D = 50 A pulsed$

parameter: V_{DD}



16 Gate charge waveforms





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Revision History

Version	Date	Changes
Version 1.0	24.07.2018	Final Data Sheet